



钜地半导体
Tudi Semiconductor

Product Specification

TUDI- SN74LVC1G32

Single 2-Input Positive-OR Gate

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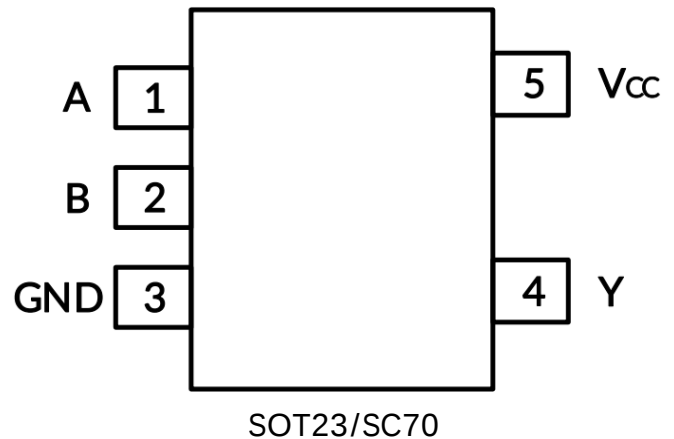
**semiconductor device
manufacturer**

- Design
- research and development
- production
- and sales



FEATURES

- Operating Voltage Range: 1.65V to 5.5V
- Low Power Consumption: 0.1 μ A (TYP)
- Operating Temperature Range:
-40 ° C to 125 ° C
- Inputs Accept Voltage to 5.5V
- High Output Drive: $\pm$ 24mA at $V_{cc}=3.0V$
- Micro SIZE PACKAGES: SOT23-5, SC70-5



APPLICATIONS

- AV Receiver
- Blu-ray Player and Home Theater
- Digital Picture Frame (DPF)
- High-Speed Data Acquisition and Generation
- Personal Navigation Device (GPS)
- Portable Media Player

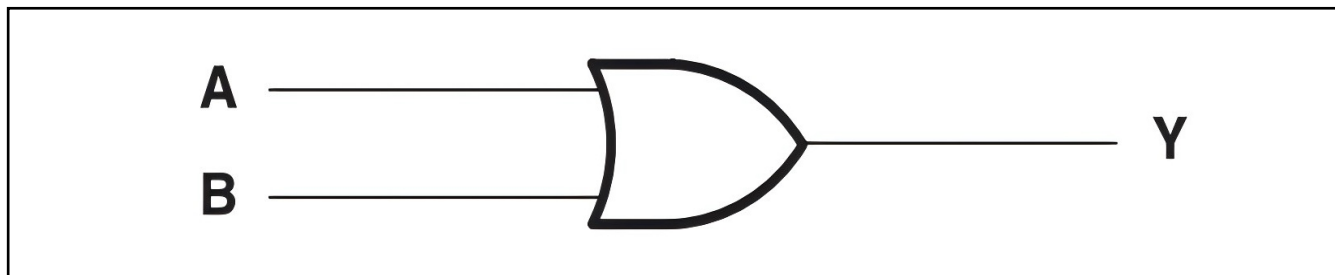
DESCRIPTIONS

The SN74LVC1G32 single 2-input positive-OR gate is designed for 1.65V to 5.5V V_{cc} operation. The SN74LVC1G32 device performs the Boolean function $Y=A + B$ or $Y=A \bullet B$ in positive logic. The device is fully specified for partial-power-down applications using Ioff. The Ioff circuitry disables the outputs, preventing damaging current backflow through the device when it is powered down.

The SN74LVC1G32 is available in Green SOT23-5 and SC70-5 packages. It operates over an ambient temperature range of -40 ° C to 125 ° C.



LOGIC SYMBOL



FUNCTION TABLE

INPUTS		OUTPUT
A	B	Y
H	H	H
L	H	H
H	L	H
L	L	L

$$Y=A+B$$

H=High Voltage Level

L=Low Voltage Level

PIN CONFIGURATION AND FUNCTIONS (TOP VIEW)

PIN	NAME	I/O	FUNCTION
1	A	I	Input
2	B	I	Input
3	GND	-	Ground Pin
4	Y	O	Y Output
5	V _{cc}	-	Power Pin



Absolute Maximum Ratings

over operating free-air temperature range (unless otherwise noted) (1) (2)

		MIN	MAX	UNIT
V_{CC}	Supply voltage range	-0.5	6.5	V
V_I	Input voltage range(2)	-0.5	6.5	V
V_O	Voltage range applied to any output in the high-impedance or power-off state(2)	-0.5	6.5	V
V_O	Voltage range applied to any output in the high or low state (2)(3)	-0.5	$V_{CC}+0.5$	V
I_{IK}	Input clamp current $V_I < 0$		-50	mA
I_{OK}	Output clamp current $V_O < 0$		-50	mA
I_O	Continuous output current		± 50	mA
	Continuous current through Vcc or GND		± 100	mA

Package Thermal Impedance

	PARAMETER	MIN	MAX	UNIT
θ_{JA}	Package thermal impedance(4)	SOT23-5 SC70-5	230 380	/W

Temperature

	PARAMETER	MIN	MAX	UNIT
Temperature	Junction temperature, T_J (5)	-65	150	
	Storage temperature, T_{stg}	-65	150	

ESD Ratings

The following ESD information is provided for handling of ESD-sensitive devices in an ESD protected area only.

	VALUE	UNIT
Human-Body Model(HBM)	± 8000	V
Charged-Device Model (CDM)	± 1500	
Machine Model(MM)	± 350	



ESD SENSITIVITY CAUTION



ESD damage can range from subtle performance degradation to complete device failure. Precision integrated circuits may be more susceptible to damage because very small parametric changes could cause the device not to meet its published specifications.

NOTE:

- (1) Stresses beyond those listed under Absolute Maximum Ratings may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under Recommended Operating Conditions is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.
- (2) The input and output negative-voltage ratings may be exceeded if the input and output current ratings are observed.
- (3) The value of V_{CC} is provided in the Recommended Operating Conditions table.
- (4) The package thermal impedance is calculated in accordance with JEDEC-51.
- (5) The maximum power dissipation is a function of $T_{J(MAX)}$, $R_{\theta JA}$, and T_A . The maximum allowable power dissipation at any ambient temperature is $P_D = (T_{J(MAX)} - T_A) / R_{\theta JA}$. All numbers apply for packages soldered directly onto a PCB.



ELECTRICAL CHARACTERISTICS

over recommended operating free-air temperature range (TYP values are at $T_A = +25^\circ\text{C}$, unless otherwise noted.) (1)

Recommended Operating Conditions

PARAMETER	SYMBOL	TEST CONDITIONS	MIN	MAX	UNIT
Supply voltage	V_{CC}	Operating	1.65	5.5	V
		Data retention only	1.5	5.5	
High-level input voltage	V_{IH}	$V_{CC}=1.65\text{V to }1.95\text{V}$	$0.65 \times V_{CC}$		V
		$V_{CC}=2.3\text{V to }2.7\text{V}$	1.7		
		$V_{CC}=3\text{V to }3.6\text{V}$	2.2		
		$V_{CC}=4.5\text{V to }5.5\text{V}$	$0.7 \times V_{CC}$		
Low-level input voltage	V_{IL}	$V_{CC}=1.65\text{V to }1.95\text{V}$		$0.15 \times V_{CC}$	V
		$V_{CC}=2.3\text{V to }2.7\text{V}$		0.3	
		$V_{CC}=3\text{V to }3.6\text{V}$		0.4	
		$V_{CC}=4.5\text{V to }5.5\text{V}$		$0.15 \times V_{CC}$	
Input voltage	V_I		0	5.5	V
Output voltage	V_O		0	V_{CC}	V
Input transition rise or fall	t_r, t_f	$V_{CC}=1.8\text{V} \pm 0.15\text{V}, 2.5\text{V} \pm 0.2\text{V}$		20	ns/V
		$V_{CC}=3.3\text{V} \pm 0.3\text{V}$		10	
		$V_{CC}=5\text{V} \pm 0.5\text{V}$		5	
Operating temperature	T_A		-40	+125	

(1) All unused inputs of the device must be held at V_{CC} or GND to ensure proper device operation.



DC Characteristics

PARAMETER	TEST CONDITIONS	V _{cc}	TEMP	MIN(2)	TYP(3)	MAX(2)	UNIT
V _{OH}	I _{OH} = -100μA	1.65V to 5.5V	Full	V _{cc} -0.1			V
	I _{OH} = -4mA	1.65V		1.2			
	I _{OH} = -8mA	2.3V		1.9			
	I _{OH} = -16mA			2.4			
	I _{OH} = -24mA	3V		2.3			
	I _{OH} = -32mA	4.5V		3.8			
V _{OL}	I _{OL} = 100μA	1.65V to 5.5V	Full			0.1	V
	I _{OL} = 4mA	1.65V				0.45	
	I _{OL} = 8mA	2.3V				0.3	
	I _{OL} = 16mA					0.4	
	I _{OL} = 24mA	3V				0.55	
	I _{OL} = 32mA	4.5V				0.55	
I _I A or B inputs	V _I = 5.5V or GND	0V to 5.5V	+25		± 0.1		μA
			Full			±5	
I _{off}	V _I or V _O = 5.5V	0	+25		± 0.1		μA
			Full			±10	
I _{cc}	V _I = 5.5V or GND, I _O = 0	1.65V to 5.5V	+25		0.1		μA
			Full			10	
I _{cc}	One input at V _{cc} -0.6V, Other inputs at V _{cc} or GND	3V to 5.5V	Full			500	μA

(1) All unused inputs of the device must be held at V_{cc} or GND to ensure proper device operation.

(2) Limits are 100% production tested at 25°C. Limits over the operating temperature range are ensured through correlations using statistical quality control (SQC) method.

(3) Typical values represent the most likely parametric norm as determined at the time of characterization. Actual typical values may vary over time and will also depend on the application and configuration.



AC Characteristics

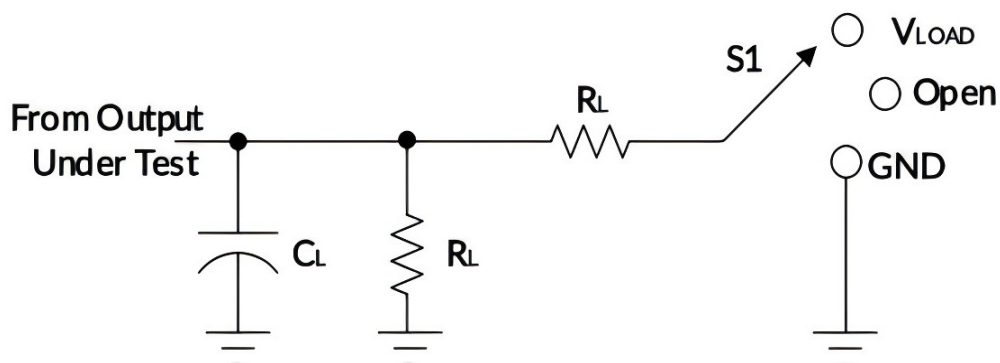
PARAMETER	SYMBOL	TEST CONDITIONS		TEMP	MIN(2)	TYP(3)	MAX(2)	UNIT
Propagation Delay	t_{pd}	$V_{cc}=1.8V\pm0.15V$	$C_L=30pF, R_L=1k\Omega$	Full		8.0		ns
		$V_{cc}=2.5V\pm0.2V$	$C_L=30pF, R_L=500\Omega$	Full		3.7		
		$V_{cc}=3.3V\pm0.3V$	$C_L=50pF, R_L=500\Omega$	Full		2.5		
		$V_{cc}=5V\pm0.5V$	$C_L=50pF, R_L=500\Omega$	Full		2.7		
Input Capacitance	C_i	$V_{cc}=3.3V$	$V_I=V_{cc}$ or GND	Full		4		pF
Power dissipation capacitance	C_{pd}	$V_{cc}=1.8V$	$f=10MHz$	+25		20		pF
		$V_{cc}=2.5V$				21		
		$V_{cc}=3.3V$				22		
		$V_{cc}=5V$				25		

(1) All unused inputs of the device must be held at V_{cc} or GND to ensure proper device operation.

(2) This parameter is ensured by design and/or characterization and is not tested in production.

(3) Typical values represent the most likely parametric norm as determined at the time of characterization. Actual typical values may vary over time and will also depend on the application and configuration.

PARAMETER MEASUREMENT INFORMATION

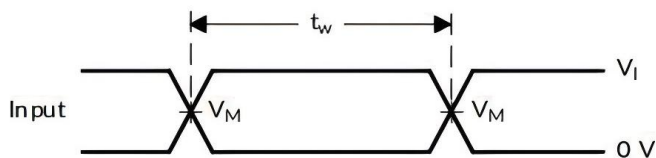




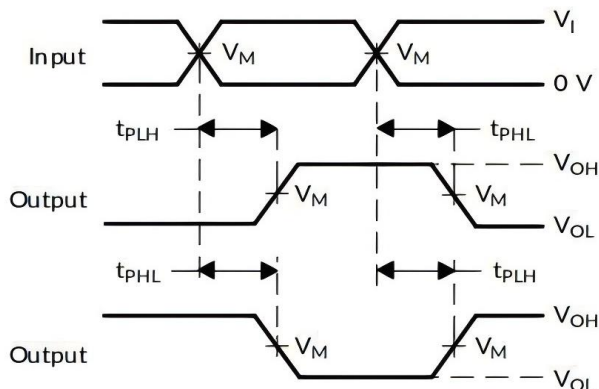
TEST	S1
t_{pLH}/t_{pHL}	Open
t_{pLz}/t_{pZL}	V_{LOAD}
t_{pHz}/t_{pZH}	GND

INPUTS

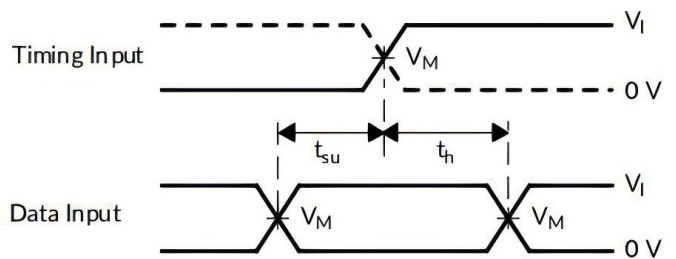
V_{cc}	V_I	t_r/t_f	V_M	V_{LOAD}	C_L	R_L	V
$1.8V \pm 0.15V$	V_{cc}	$\leq 2ns$	$V_{cc}/2$	$2 \times V_{cc}$	30pF	1k Ω 2	0.15V
$2.5V \pm 0.2V$	V_{cc}	$\leq 2ns$	$V_{cc}/2$	$2 \times V_{cc}$	30pF	500 Ω	0.15V
$3.3V \pm 0.3V$	3V	$\leq 2.5ns$	1.5V	6V	50pF	500 Ω	0.3V
$5V \pm 0.5V$	V_{cc}	$\leq 2.5ns$	$V_{cc}/2$	$2 \times V_{cc}$	50pF	500 Ω	0.3V



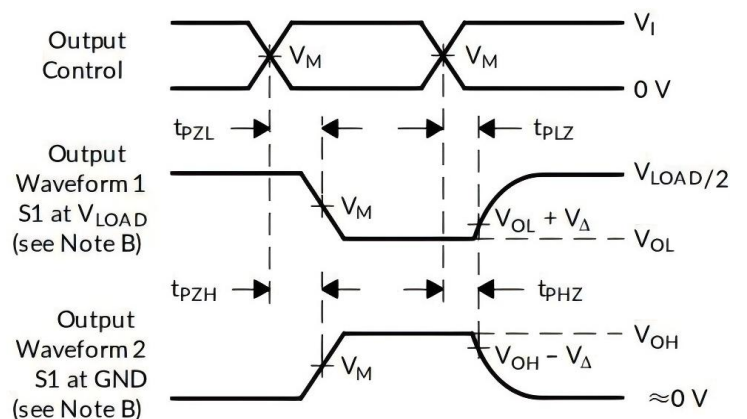
VOLTAGE WAVEFORMS PULSE DURATION



VOLTAGE WAVEFORMS PROPAGATION DELAY TIMES INVERTING AND NONINVERTING OUTPUTS



VOLTAGE WAVEFORMS SETUP AND HOLD TIMES



VOLTAGE WAVEFORMS ENABLE AND DISABLE TIMES LOW-AND HIGH-LEVEL ENABLING

Figure 1. Load Circuit and Voltage Waveforms



NOTES: A. C_L includes probe and jig capacitance.

B. Waveform 1 is for an output with internal conditions such that the output is low, except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high, except when disabled by the output control.

C. All input pulses are supplied by generators having the following characteristics: $PRR \leq 10 \text{ MHz}$, $Z_o = 50\Omega$.

D. The outputs are measured one at a time, with one transition per measurement.

E. t_{PLZ} and t_{PHZ} are the same as t_{dis} .

F. t_{PZL} and t_{PZH} are the same as t_{en} .

G. t_{PLH} and t_{PHL} are the same as t_{pd} .

H. All parameters and waveforms are not applicable to all devices.



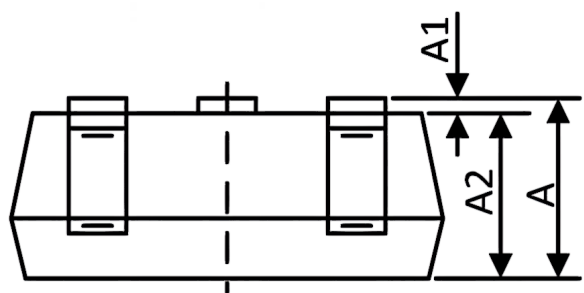
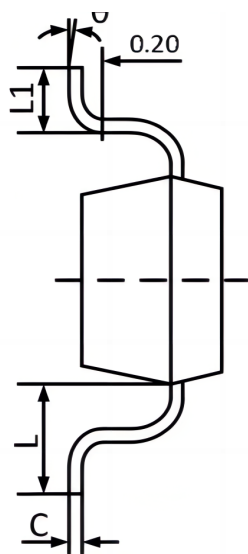
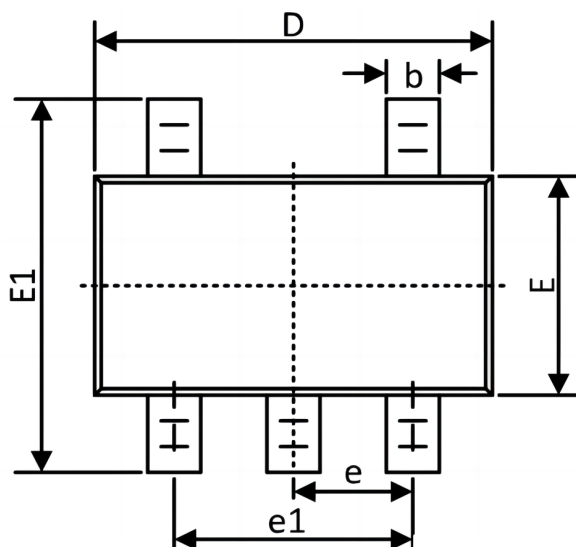
Order information

Order Number	Package	Package Quantity	Marking On The park	Temperature
SN74LVC1G32DCKR-TUDI	SC70-5	Tape,Reel,3000	CG5	-40°C~125°C
SN74LVC1G32DBVR-TUDI	SOT23-5	Tape,Reel,3000	C32R	

Revision history

	Date	Revision	Page
V1.0	2018/5/14	New	1-14

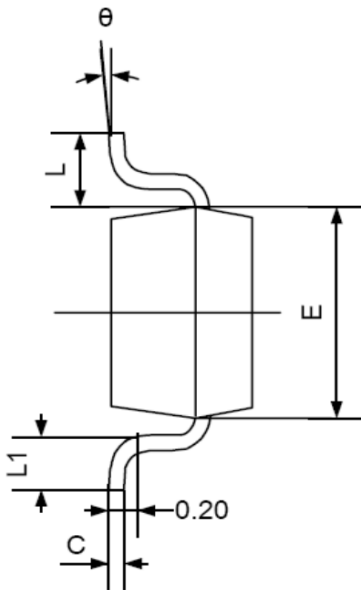
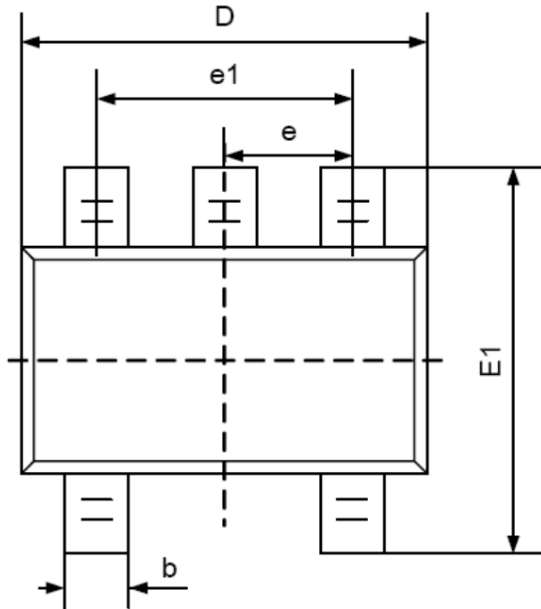
Package SOT23-5



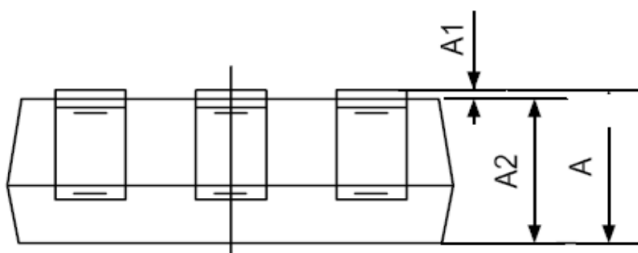
Symbol	Dimensions In Millimeters		Dimensions In Inches	
	MIN	MAX	MIN	MAX
A	1.050	1.250	0.041	0.049
A1	0.000	0.100	0.000	0.004
A2	1.050	1.150	0.041	0.045
b	0.300	0.400	0.012	0.016
C	0.100	0.200	0.004	0.008
D	2.820	3.020	0.111	0.119
E	1.500	1.700	0.059	0.067
E1	2.650	2.950	0.104	0.116
e	0.950TYP		0.037TYP	
e1	1.800	2.000	0.071	0.079
L	0.700REF		0.028REF	
L1	0.300	0.600	0.012	0.024
θ	0°	8°	0°	8°



Package SC70-5



Symbol	DimensionsIn Millimeters		DimensionsIn Inches	
	Min	Max	Min	Max
A	0.900	1.100	0.035	0.043
A1	0.000	0.100	0.000	0.004
A2	0.900	1.000	0.035	0.039
b	0.150	0.350	0.006	0.014
C	0.080	0.150	0.003	0.006
D	2.000	2.200	0.079	0.087
E	1.150	1.350	0.045	0.053
E1	2.150	2.450	0.085	0.096
e	0.650TYP		0.026TYP	
e1	1.200	1.400	0.047	0.055
L	0.525REF		0.021REF	
L1	0.260	0.460	0.010	0.018
theta	0°	8°	0°	8°





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